



Session Title:	[ThG1] Frontier Metrology and Modeling VI
Session Date:	November 14 (Thu.), 2024
Session Time:	09:30-10:35
Session Room:	Room G (Meeting Room, 5F, Grand Josun Busan)
Session Chair:	Prof. Tae-Hun Shim (Hanyang Univ., Korea)

[ThG1-1] [Invited]

09:30-09:55

Recent Progress in Optical Metrology and Data Manipulating Techniques of AI: AI Combined Optical Metrology

Shinyoung Ryu, Junje Seong (Auros Tech. Inc., Korea), Jongjeong Kim (Haedosa Inc., Korea), Jiwon Lee (Auros Tech. Inc., Korea), and Kwangwoo Kim (Haedosa Inc., Korea)

[ThG1-2]

09:55-10:15

Responses of Various Electrical Trap Measurement Methods to Grain Boundary Traps

Joohee Oh (Sungkyunkwan Univ., Korea), Myeong Geun Cha (Samsung Display Co., Ltd., Korea), and Hyoungsub Kim (Sungkyunkwan Univ., Korea)

[ThG1-3]

10:15-10:35

Spectral and Imaging Sensors for Diagnostics in Next-Generation Semiconductor Processes

Youngho Cho, Chang Sug Lee, and Keun Oh Park (Korea Spectral Products Co., Ltd., Korea)